PowerPhase, Dual N-Channel SO8FL

30 V, High Side 20 A / Low Side 32 A

Features

- Co-Packaged Power Stage Solution to Minimize Board Space
- Minimized Parasitic Inductances
- Optimized Devices to Reduce Power Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Converters
- System Voltage Rails
- Point of Load

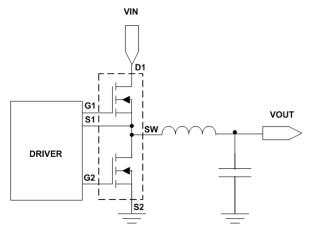


Figure 1. Typical Application Circuit

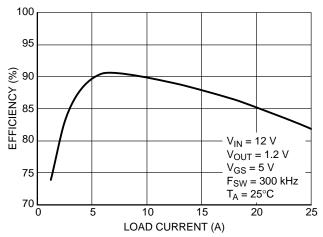


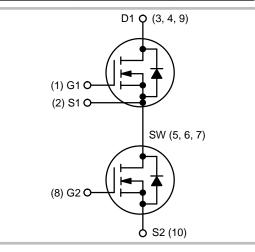
Figure 2. Typical Efficiency Performance POWERPHASEGEVB Evaluation Board



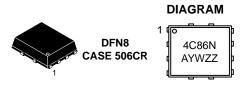
ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
Q1 Top FET	5.4 mΩ @ 10 V	20.4
30 V	8.1 mΩ @ 4.5 V	20 A
Q2 Bottom	2.6 mΩ @ 10 V	32 A
FET 30 V	3.4 mΩ @ 4.5 V	32 A



PIN CONNECTIONS D1 4 5 5 SW D1 3 9 10 6 SW S1 2 7 SW G1 1 6 SW (Bottom View)



4C86N = Specific Device Code A = Assembly Location Y = Year

W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

See detailed ordering and shipping information on page 10 of this data sheet.

MARKING

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter		Symbol	Value	Unit			
Drain-to-Source Voltage	Q1	V _{DSS}	30	V			
Drain-to-Source Voltage	Q2						
Gate-to-Source Voltage	Q1	V _{GS}	±20	V			
Gate-to-Source Voltage			Q2				
Continuous Drain Current R _{0JA} (Note 1)		T _A = 25°C	Q1	I _D	14.8		
		T _A = 85°C	1		10.7	1	
		T _A = 25°C	Q2		23.7	A	
		T _A = 85°C	1		17.1		
Power Dissipation	1	T _A = 25°C	Q1	P_{D}	1.89	W	
RθJA (Note 1)			Q2				
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s (Note 1)}$	1	T _A = 25°C	Q1	I _D	20.2		
		T _A = 85°C			14.5	A A	
	Steady	T _A = 25°C	Q2		32.3		
	State	T _A = 85°C	1		23.3		
Power Dissipation	1	T _A = 25°C	Q1	P_{D}	3.51	W	
$R_{\theta JA} \le 10 \text{ s (Note 1)}$			Q2				
Continuous Drain Current	1	T _A = 25°C	Q1	I _D	11.3		
R _{θJA} (Note 2)		T _A = 85°C	1		8.1	1 .	
		T _A = 25°C	Q2		18.1	A	
		T _A = 85°C	1		13.0	7	
Power Dissipation	1	T _A = 25 °C	Q1	P_{D}	1.10	W	
R _{θJA} (Note 2)			Q2				
Pulsed Drain Current		T _A = 25°C	Q1	I _{DM}	160	Α	
		t _p = 10 μs	Q2		280		
Operating Junction and Storage Temperature		•	Q1	T _J , T _{STG}	-55 to +150	°C	
	Q2						
Source Current (Body Diode)	Q1	I _S	10	А			
	Q2		10				
Drain to Source DV/DT		dV/dt	6	V/ns			
Single Pulse Drain-to-Source Avalanche Energy (T.	Q1	EAS	20	mJ			
$V_{DD} = 50 \text{ V}, V_{GS} = 10 \text{ V}, L = 0.1 \text{ mH}, R_G = 25 \Omega$	Q2	EAS	80	1			
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		T _L	260	°C			

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface—mounted on FR4 board using 1 sq—in pad, 2 oz Cu.

2. Surface—mounted on FR4 board using the minimum recommended pad size of 100 mm².

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	66.0	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	113.7	°C/W
Junction-to-Ambient - (t ≤ 10 s) (Note 3)	$R_{\theta JA}$	35.6	

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Co	ondition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	•		•
Drain-to-Source Break-	Q1		V _{GS} = 0 V, I _D = 250 μA		30			V
down Voltage	Q2	V _{(BR)DSS}			30			
Drain-to-Source Break-	Q1	V _{(BR)DSS}				17		mV /
down Voltage Temperature Coefficient	Q2	/T _J				16.5		°C
Zero Gate Voltage Drain	Q1	I _{DSS}	$V_{GS} = 0 V$	T _J = 25°C			1	
Current			$V_{DS} = 24 \text{ V}$	T _J = 125°C			10	μA
	Q2		V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25°C			1	μι
Gate-to-Source Leakage	Q1	I _{GSS}	$V_{GS} = 0 V$	VDS = ±20 V			100	A
Current	Q2						100	nA
ON CHARACTERISTICS (Not	e 5)							
Gate Threshold Voltage	Q1	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		1.3		2.2	V
	Q2				1.3		2.2	
Negative Threshold Temper-	Q1	V _{GS(TH)} / T _J				4.5		mV /
ature Coefficient	Q2	IJ				4.6		°C
Drain-to-Source On Resist-	Q1	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		4.3	5.4	
ance			$V_{GS} = 4.5 \text{ V}$	I _D = 18 A		6.5	8.1	
	Q2		V _{GS} = 10 V	I _D = 30 A		1.7	2.6	mΩ
			$V_{GS} = 4.5 \text{ V}$ $I_D = 12.5 \text{ A}$			2.4	3.4	
CAPACITANCES								
Input Capacitance	Q1	Corre				1153		
input Capacitance	Q2	C _{ISS}				1541		
Output Canacitanas	Q1	C _{OSS}	V = 0 V f = 1 MH= V 45 V			532		pF
Output Capacitance		OSS	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, V}_{DS} = 15 \text{ V}$			764		
Reverse Capacitance	Q1	Cana	7			107		
Neverse Capacitance	rse Capacitance Q2		C _{RSS}			42]

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

6. Switching characteristics are independent of operating junction temperatures.

Surface–mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
 Surface–mounted on FR4 board using the minimum recommended pad size of 100 mm².

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Co	ondition	Min	Тур	Max	Unit	
CHARGES, CAPACITANCES	& GATE	RESISTANC	E				•		
T. 10 1 01	Q1					10.9			
Total Gate Charge	Q2	$Q_{G(TOT)}$				21.6			
T	Q1	_				1.2			
Threshold Gate Charge	Q2	Q _{G(TH)}	V 45VV	45.77.1 00.4		1.4			
0-1-1-0	Q1	_	$V_{GS} = 4.5 \text{ V}, V_{DS}$	= 15 V; I _D = 30 A		3.4		nC	
Gate-to-Source Charge	Q2	Q_GS				8.6			
Onto to Danie Observe	Q1	0				5.4			
Gate-to-Drain Charge	Q2	Q_GD				5.5			
T. 10 . 0	Q1			45.77.1 00.4		22.2			
Total Gate Charge	Q2	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS}$	= 15 V; I _D = 30 A		47.5		nC	
0 . 5	Q1	R_{G}	_			1.0			
Gate Resistance	Q2		I _A =	25°C		1.0		Ω	
SWITCHING CHARACTERIS	STICS (No	te 6)					•		
T 0 D T	Q1					8.9			
Turn-On Delay Time	Q2	t _{d(ON)}	_			8.3			
D: T	Q1					21.2			
Rise Time	Q2	t _r	V _{GS} = 4.5 V	V _{DS} = 15 V,		15.1		ns ns	
T 0"P T	Q1	,	$I_{D} = 15 \text{ A},$	$V_{DS} = 15 V$, $R_G = 3.0 \Omega$		15.3			
Turn-Off Delay Time	Q2	t _{d(OFF)}	d(OFF)			19.3		1	
5 U.T.	Q1	,				4.4		1	
Fall Time	Q2	t _f				4.2		1	
SWITCHING CHARACTERIS	STICS (No	te 6)							
T O. Dalas Tara	Q1					6.7			
Turn-On Delay Time	Q2	t _{d(ON)}				6.3			
D'e e T'e e	Q1					19.5			
Rise Time	Q2	t _r	V _{GS} = 10 V,	$V_{DS} = 15 \text{ V},$		13.8		1	
- 0"5 -	Q1	,	$I_{\rm D} = 15 \rm A,$	$R_G = 3.0 \Omega$		20.1		ns	
Turn-Off Delay Time	Q2	t _{d(OFF)}	t _d (OFF)		22				
	Q1					2.8		1	
Fall Time	Q2	t _f				3.2			
DRAIN-SOURCE DIODE CH	ARACTE	RISTICS				-	<u>-</u>	<u>-</u>	
			$V_{GS} = 0 V$	T _J = 25°C		0.80			
- W.	Q1	,,	$V_{GS} = 0 V$, $I_S = 10 A$	T _J = 125°C		0.60			
Forward Voltage	6.5	V_{SD}	V _{GS} = 0 V,	T 0500		0.78	V		
	Q2		I _S = 10 A	T _J = 125°C		0.62		1	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Condition	Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS							
Daviera Daviera Tima	Q1						
Reverse Recovery Time	Q2	t _{RR}			33.7		ns
Charma Time	Q1	ta			14.5		
Charge Time	Q2				17.4		
Dischause Times	Q1	4 la	$V_{GS} = 0 \text{ V}, d_{IS}/d_t = 100 \text{ A/}\mu\text{s}, I_S = 30 \text{ A}$		14.6		
Discharge Time	Q2	tb			16.3		
Daviera Danaviani Chare	Q1	0			21		0
Reverse Recovery Charge	Q2	Q_{RR}			27.5		nC

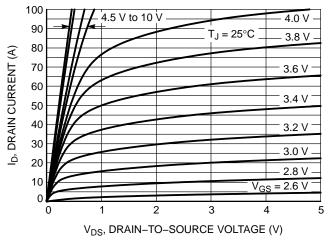
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$. 6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS - Q1

100

90

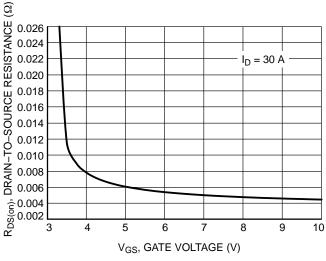
 $V_{DS} = 3 V$



80 ID, DRAIN CURRENT (A) 70 60 50 40 30 20 $T_J = 125^{\circ}C$ 10 $T_J = -55^{\circ}C$ $T_J = 25^{\circ}C$ 0.5 2.5 3.0 3.5 4.0 4.5 5.0 5.5 1.0 1.5 2.0 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 3. On-Region Characteristics

Figure 4. Transfer Characteristics



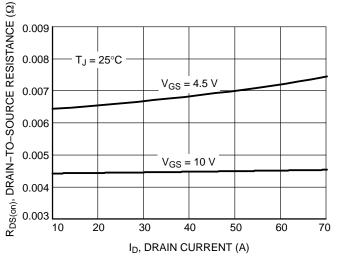
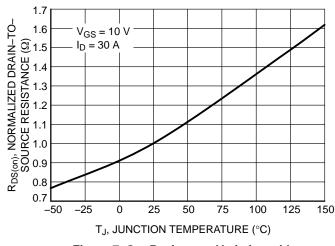


Figure 5. On-Resistance vs. Gate-to-Source Voltage

Figure 6. On-Resistance vs. Drain Current and Gate Voltage



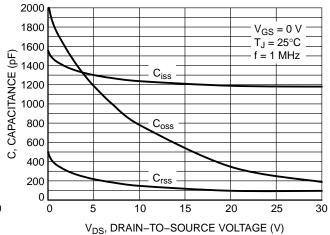


Figure 7. On–Resistance Variation with Temperature

Figure 8. Capacitance Variation

TYPICAL CHARACTERISTICS - Q1

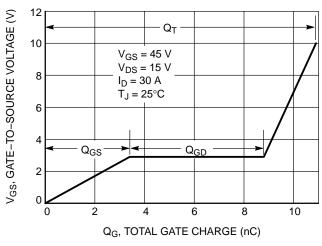


Figure 9. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

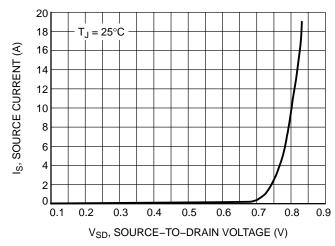


Figure 10. Diode Forward Voltage vs. Current

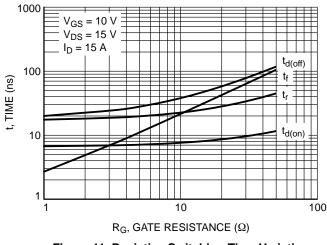


Figure 11. Resistive Switching Time Variation vs. Gate Resistance

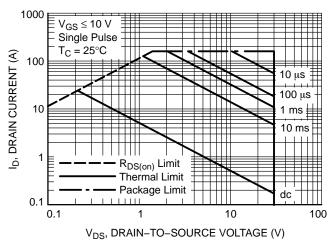


Figure 12. Maximum Rated Forward Biased Safe Operating Area

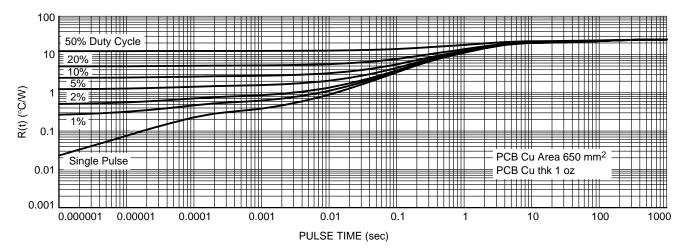
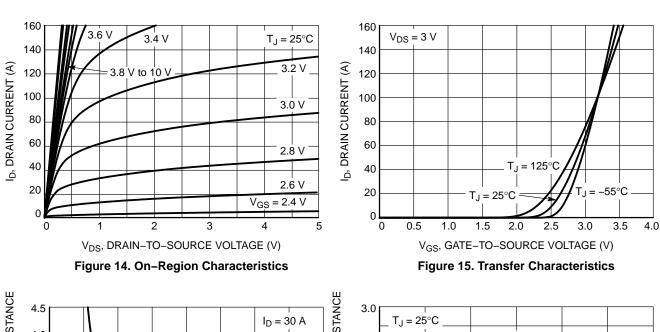
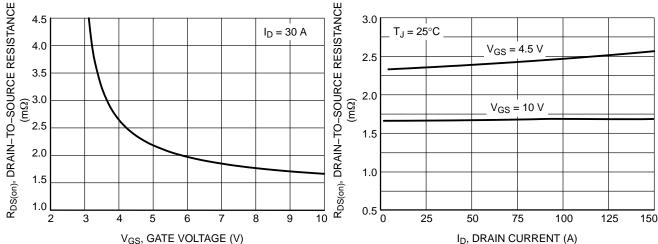
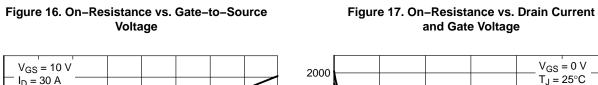


Figure 13. Thermal Characteristics

TYPICAL CHARACTERISTICS - Q2







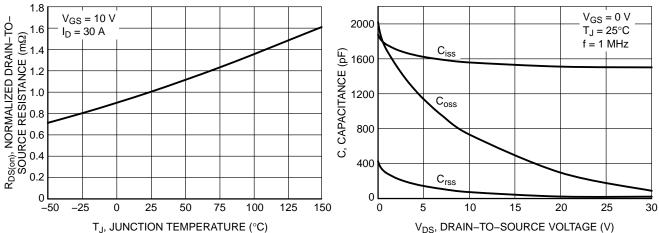


Figure 18. On–Resistance Variation with Temperature

Figure 19. Capacitance Variation

TYPICAL CHARACTERISTICS - Q2

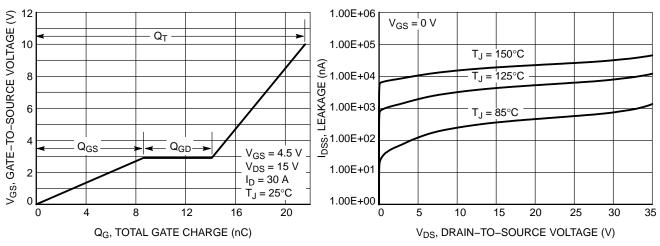


Figure 20. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

Figure 21. Drain-to-Source Leakage Current vs. Voltage

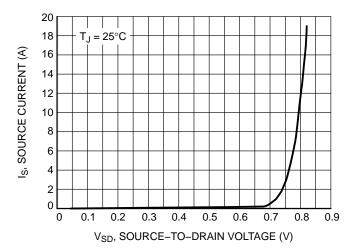


Figure 22. Diode Forward Voltage vs. Current

TYPICAL CHARACTERISTICS - Q2

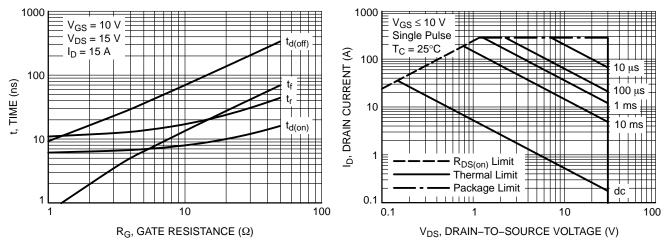


Figure 23. Resistive Switching Time Variation vs. Gate Resistance

Figure 24. Maximum Rated Forward Biased Safe Operating Area

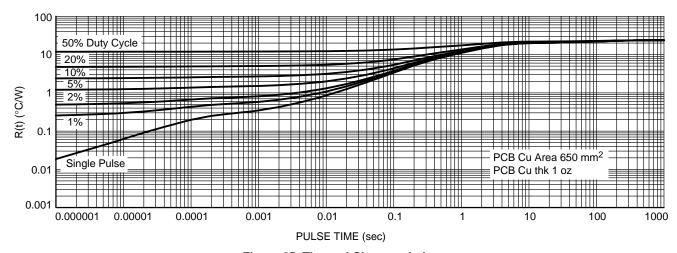


Figure 25. Thermal Characteristics

ORDERING INFORMATION

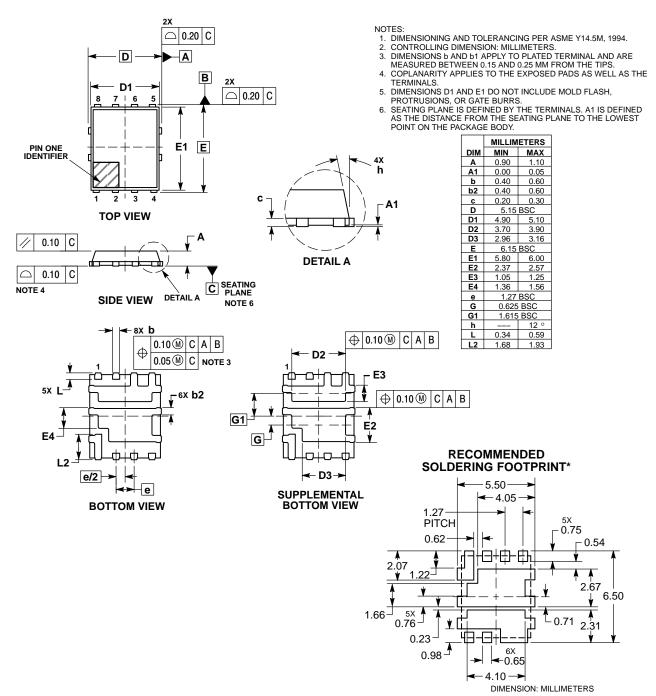
Device	Package	Shipping [†]
NTMFD4C86NT1G	DFN8 (Pb-Free)	1500 / Tape & Reel
NTMFD4C86NT3G	DFN8 (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

DFN8 5x6, 1.27P PowerPhase FET

CASE 506CR ISSUE B



^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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